

Special Issue

Selected Papers from the 1st International Conference of the Chinese Society of Micro/Nano Technology

Message from the Guest Editor

Summary The 1st International Conference of the Chinese Society of Micro/Nano Technology The 1st International Conference of the Chinese Society of Micro/Nano Technology was held in Beijing, China on November 19-21, 2008. The conference brought together top researchers from around the world to exchange research results and address open issues in all aspects of micro/nano technology. This special issue collects best papers from more than 300 contributions.

Guest Editor

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Deadline for manuscript submissions

closed (15 March 2009)



Sensors

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Impact Factor 4.0
CiteScore 9.4
Indexed in PubMed



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Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. *Sensors* organizes Special Issues devoted to specific sensing areas and applications each year.

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